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	Application No.	Applicant(s)	m_
Notice of Allowability	09/880,089 Examin r	YAMAZAKI ET AL. Art Unit	
	DAVID VU	2818	
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS serewith (or previously mailed), a Notice of Allowance (PTOL-88 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT I of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED ir 5) or other appropriate commu RIGHTS. This application is s	this application. If not included unication will be mailed in due course.	THIS initiative
. \boxtimes This communication is responsive to <u>09/12/03</u> .			
2. ☑ The allowed claim(s) is/are <u>1-60</u> .			
B. \boxtimes The drawings filed on <u>14 June 2002</u> are accepted by the			
 Acknowledgment is made of a claim for foreign priority of a)	under 35 U.S.C. § 119(a)-(d) (or (f).	
 Certified copies of the priority documents have 	ve been received.		
Certified copies of the priority documents have	ve been received in Application	n No	
3. Copies of the certified copies of the priority d	locuments have been received	d in this national stage application fron	n the
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
 Acknowledgment is made of a claim for domestic priority reference was included in the first sentence of the specifi 	cation or in an Application Da	ta Sheet. 37 CFR 1.78.	ific
(a) The translation of the foreign language provisional			
Acknowledgment is made of a claim for domestic priority in the first sentence of the specification or in an Application	under 35 U.S.C. §§ 120 and/on Data Sheet. 37 CFR 1.78.	or 121 since a specific reference was i	included
Applicant has THREE MONTHS FROM THE "MAILING DATE" pelow. Failure to timely comply will result in ABANDONMENT of	of this communication to file a of this application. THIS THR	a reply complying with the requirement EE-MONTH PERIOD IS NOT EXTEN	s noted IDABLE.
 A SUBSTITUTE OATH OR DECLARATION must be sub INFORMAL PATENT APPLICATION (PTO-152) which gi 	mitted. Note the attached EXA ives reason(s) why the oath o	AMINER'S AMENDMENT or NOTICE r declaration is deficient.	OF
3. CORRECTED DRAWINGS (as "replacement sheets") m			
(a) ☐ including changes required by the Notice of Draftspe	erson's Patent Drawing Review	w (PTO-948) attached	•
1) ☐ hereto or 2) ☐ to Paper No			
(b) ☐ including changes required by the proposed drawing			
(c) ☐ including changes required by the attached Examine	er's Amendment / Comment of	r in the Office action of Paper No	 ·
Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in	: 1.84(c)) should be written on t n the margin according to 37 Cl	he drawings in the front (not the back) o -R 1.121(d).	of
9. DEPOSIT OF and/or INFORMATION about the department attached Examiner's comment regarding REQUIREMENT FOR	posit of BIOLOGICAL MAT THE DEPOSIT OF BIOLOGI	ERIAL must be submitted. Note the CAL MATERIAL.	9
Attachm nt(s)			
1☐ Notice of References Cited (PTO-892)	5☐ Notice of Info	ormal Patent Application (PTO-152)	
2 Notice of Draftperson's Patent Drawing Review (PTO-948)	6☐ Interview Su	mmary (PTO-413), Paper No	
Information Disclosure Statements (PTO-1449 or PTO/SB/	00)	Amendment/Comment	
Paper No. <u>09/15/03</u>		Statement of Reasons for Allowance	
4 Examiner's Comment Regarding Requirement for Deposit of Biological Material	9☐ Other	Statement of Readons for Allowance	
o, biological Material	(d) Silier	•	

David Nelms
Supervisory Patent Examiner
Technology Center 2800

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DETAILED ACTION

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Reason for allowance

1. The following is an examiner's statement of reason for allowance: None of the references of record teaches or suggests a semiconductor device comprising thin film transistors in a pixel portion and in a driver circuit formed over a same insulating surface, semiconductor device comprising: a plurality of crystal planes as measured by EBSP method in which an electron beam of 20 nm or less in a spot diameter is irradiated to a plurality of different points of channel-forming region, wherein ratios of plurality of crystal planes which form an angle equal to or less than 10° with a substrate surface is larger or equal to 20% in [101] plane, less than or equal to 3% in [001] plane, and less than or equal to 5% in [111] plane.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

Conclusion

2. Any inquiry concerning this communication or earlier communications from the examiner should be directed to David Vu whose telephone number is 703-305-0391. The new

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phone number after January 08, 2004 will be (571) 272-1798. The examiner can normally be reached on Monday-Friday 8:00am-5:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on 703-308-4910. The new phone number after January 08, 2004 will be (571) 272-1787.

The fax phone numbers for the organization where this application or proceeding is assigned is (703) 308-7722 for regular communications and for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

PV

David Vu.

Bavid Nelms
Supervisory Patent Examiner
Technology Center 2800